
S-W07

Synchrotron X-ray scattering analysis of interfaces and nanostructures

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Synchrotron x-ray scattering is a powerful tool to probe interfaces and nanostructures. In this talk, three different cases of structural analysis utilizing synchrotron x-ray scattering will be presented; (1) the structural analysis of Pb nanocrystals grown on Si(111) at low-temperature, (2) the diffuse scattering analysis of nanovacancies in low-temperature grown homoepitaxial Ag films on Ag(001), (3) the structural analysis of GaN nano-grains grown on miscut sapphire substrates with emphasis on the long-range ordering and strain relaxation of the nanograins.